

**Amendments to the Specification:**

Please replace paragraph [024] with the following amended paragraph:

[024] Figure 4 shows an example of an alternative arrangement of test modules 10 with a dual-site DIB 32. Two at-speed digital test modules 10 are shown coupled to two test sockets 30. Figure [[3]] 5 illustrates an example of another alternative configuration embodying the invention. A typical socket 30, DIB 32, and DUT 18 arrangement as shown may be used with a testing module 10 configured for disposition between a DIB 32 and ATE 20 generally known in the arts. The module 10 is configured for making electrical contact at the interface 34 between the DIB 14 and ATE 18 by means of pogo pins, a probe membrane, or other suitable means. The examples of preferred embodiments of the invention shown and described are presented to illustrate and explain the principles and operation of the invention. It should be understood by those skilled in the arts that there are numerous possible alternative implementations of the principles of the invention. The examples shown and described are included to present features and advantages of various implementations of the invention and are not intended to be construed in a limiting sense.